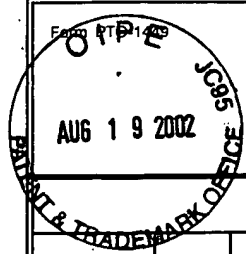


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| LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | | | APPLICANT Kie Y. Ahn et al. | |
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| U.S. PATENT DOCUMENTS | | | | | | | |
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| EXAMINER <i>Erik Kuehn</i> | | | | DATE CONSIDERED <i>10/5/02</i> | | | |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | |